


<b>Search Notes</b>  	<b>Application/Control No.</b>  10736838	<b>Applicant(s)/Patent Under Reexamination</b>  SON, HEE-KWAN
	<b>Examiner</b>  Almeida, Devin	<b>Art Unit</b>  2132

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST Printout	10/10/2007	DA
See EAST Printout	4/23/2008	DA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner